## Application/Control No. Applicant(s)/Patent Under Reexamination 10/712,788 DELMULLE ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 2618 Yuwen Pan **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY \* 04-2004 Pabla et al. 713/168 US-2004/0064693 Α \* Pines et al. 379/218.01 US-6,970,548 11-2005 В US-С US-D US-Ε US-F US-G Н US-US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS Document Number Date Classification Country Name Country Code-Number-Kind Code MM-YYYY Ν 0 Ρ Q R S Ţ **NON-PATENT DOCUMENTS**

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